Se	arch	Note	es	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/780,414	YU ET AL.	
Examiner	Art Unit	
Donahai D. Mauyon	2720	

SEARCHED			
Class	Subclass	Date	Examiner
29	407.04 709, 720- 722, 739 743	9/30/2006	10TV
	744, 759	ſ	
	760		
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269	8, 21		
	54.4		
<u></u>	54.5		
382	147, 149		
700	110, 114		
702	150	<b>W</b>	7
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEAR	NOTES CH STRATEGY	)
	DATE	EXMR
East Search Updated (see attachment)	9/30/2006	wi